## **Application Data Sheet**

## **Application Information**

Application number:: Unassigned

Filing Date:: 02/13/2004

Application Type:: Regular

Subject Matter:: Utility

Suggested classification::

Suggested Group Art Unit::

CD-ROM or CD-R?:: None

Computer Readable Form (CRF)?:: No

Title:: APPARATUS AND METHOD FOR THIN-

LAYER METROLOGY

Attorney Docket Number:: 016790-0489

Request for Early Publication?:: No

Request for Non-Publication?:: No

**Suggested Drawing Figure::** 

Total Drawing Sheets:: 5

Small Entity?:: No

Petition included?::

Secrecy Order in Parent Appl.?:: No

## **Applicant Information**

**Applicant Authority Type::** Inventor

Primary Citizenship Country:: Federal Republic of Germany

Status:: Full Capacity

Given Name:: Matthias

Family Name:: SLODOWSKI

City of Residence:: Jena

**Country of Residence::** Germany

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Representative Customer 22428				
Number::				
Domestic Priority Information				
Application:: Continuity Ty		Type::	Parent	Parent Filing
			Application::	Date::
Foreign Priority Information				
Country:: Application		on	Filing Date::	Priority Claimed::
	number::			
Federal Republic of	103 08 258.1		02/25/2003	Yes
Germany				

## **Assignee Information**

Assignee name:: LEICA MICROSYSTEMS JENA GmbH